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Docket No.: 049657-0875

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Tetsushi TANIZAKI, et al.

RESPONSE UNDER 37 CFR 1.116

EXPEDITED PROCEDURE

Application No.: 09/712,246

Customer No.: 20277

Confirmation No.: 8725

Filed: November 15, 2000

Group Art Unit: 2133

Examiner: M.M. Chaudry

Title: SEMICONDUCTOR MEMORY DEVICE WITH BUILT-IN SELF TEST CIRCUIT
OPERATING AT HIGH RATE

AMENDMENT UNDER 37 CFR 1.116

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

The following Remarks are submitted in response to the Office Action dated January 27, 2005, pursuant to the provisions of 37 C.F.R. § 1.116.

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 4 of this paper.

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